

FAST GATE TURN-OFF THYRISTORS

Thyristors in SOT-93 envelopes which are capable of being turned both on and off via the gate, and may be used with gate-assisted turn-off in anode-commutated circuits. They are suitable for use in resonant power supplies, high-frequency inverters, motor control etc. The devices have no reverse blocking capability; for reverse blocking operation use with a series diode, for reverse conducting operation use with an anti-parallel diode. The anode is connected to the mounting base.

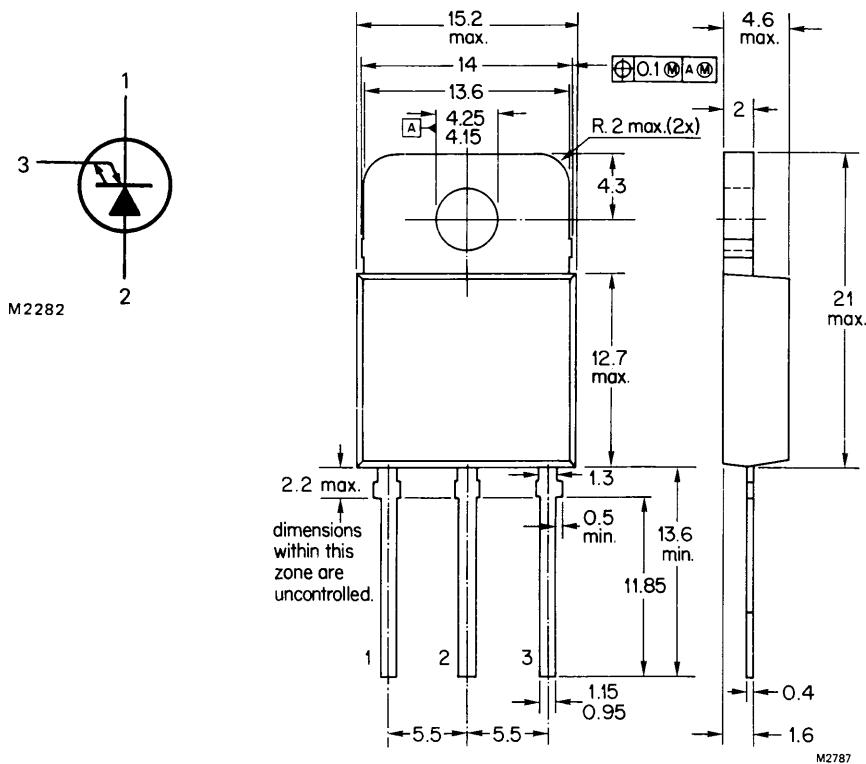
QUICK REFERENCE DATA

		BTR59-800R	1300R	
Repetitive peak off-state voltage	V _{DRM}	max.	800	1300
Controllable anode current	I _{TCRM}	max.	50	A
Average on-state current	I _{T(AV)}	max.	10	A
Circuit commutated turn-off time	t _q	<	1.0	μs

MECHANICAL DATA

Dimensions in mm

Fig.1 SOT93; anode connected to mounting base.



Accessories supplied on request; see data sheets Mounting instructions and accessories for SOT-93 envelopes.

RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC134).

Anode to cathode		BTR59-800R	1300R	
Transient off-state voltage	V_{DSM}	max. 800	1300	V*
Repetitive peak off-state voltage	V_{DRM}	max. 800	1300	V*
Working off-state voltage	V_{DW}	max. 600	1000	V*
Continuous off-state voltage	V_D	max. 400	750	V*
Average on-state current (averaged over any 20 ms period) up to $T_{mb} = 85^\circ\text{C}$	$I_T(\text{AV})$	max. 10		A
R.M.S. on-state current	$I_T(\text{RMS})$	max. 16.5		A
Controllable anode current	I_{TCRM}	max. 50		A
Non-repetitive peak on-state current $t = 10 \text{ ms}; \text{half-sinewave};$ $T_j = 120^\circ\text{C}$ prior to surge	I_{TSM}	max. 100		A
$I^2 t$ for fusing; $t = 10 \text{ ms}$	$I^2 t$	max. 50		$\text{A}^2 \text{s}$
Total power dissipation up to $T_{mb} = 25^\circ\text{C}$	P_{tot}	max. 105		W
Gate to cathode				
Repetitive peak current $T_j = 120^\circ\text{C}$ prior to surge gate-cathode forward; $t = 10 \text{ ms};$ half-sinewave	I_{GFM}	max. 25		A
gate-cathode reverse; $t = 20 \mu\text{s}$	I_{GRM}	max. 25		A
Average power dissipation (averaged over any 20 ms period)	$P_G(\text{AV})$	max. 5.0		W
Temperatures				
Storage temperature	T_{stg}	-40 to +125		$^\circ\text{C}$
Operating junction temperature	T_j	max.	120	$^\circ\text{C}$
THERMAL RESISTANCE				
From mounting base to heatsink; with heatsink compound	$R_{\text{th mb-h}}$	=	0.2	K/W
From junction to mounting base	$R_{\text{th j-mb}}$	=	0.9	K/W

*Measured with gate-cathode connected together.

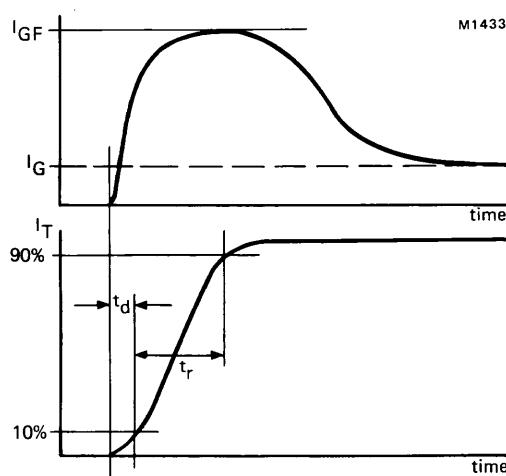
CHARACTERISTICS**Anode to cathode****On-state voltage** $I_T = 10 \text{ A}; I_G = 0.5 \text{ A}; T_j = 120^\circ\text{C}$ $V_T < 3.0 \text{ V}^*$ **Rate of rise of off-state voltage that will not trigger any off-state device; exponential method** $V_D = 2/3 V_{Dmax}; V_{GR} = 5 \text{ V}; T_j = 120^\circ\text{C}$ $dV_D/dt < 10 \text{ kV}/\mu\text{s}$ **Rate of rise of off-state voltage that will not trigger any device following conduction, linear method** $I_T = 20 \text{ A}; V_D = V_{DRMmax}; V_{GR} = 10 \text{ V}; T_j = 120^\circ\text{C}$ $dV_D/dt < 1.0 \text{ kV}/\mu\text{s}$ **Off-state current** $V_D = V_{Dmax}; T_j = 120^\circ\text{C}$ $I_D < 5.0 \text{ mA}$ **Latching current; $T_j = 25^\circ\text{C}$** $I_L \text{ typ. } 1.5 \text{ A}^{**}$ **Gate to cathode****Voltage that will trigger all devices** $V_D = 12 \text{ V}; T_j = 25^\circ\text{C}$ $V_{GT} > 1.5 \text{ V}$ **Current that will trigger all devices** $V_D = 12 \text{ V}; T_j = 25^\circ\text{C}$ $I_{GT} > 500 \text{ mA}$ **Minimum reverse breakdown voltage** $I_{GR} = 1.0 \text{ mA}$ $V_{(BR)GR} > 10 \text{ V}$ **Switching characteristics (resistive load)****Turn-on when switched to $I_T = 10 \text{ A}$ from $V_D = 250 \text{ V}$** with $I_{GF} = 2.5 \text{ A}; T_j = 25^\circ\text{C}$ $t_d < 0.3 \mu\text{s}$ **delay time** $t_r < 1.5 \mu\text{s}$ **rise time**

Fig.2 Waveforms.

*Measured under pulse conditions to avoid excessive dissipation.

**Below latching level the device behaves like a transistor with a gain dependent on current.

Switching characteristics (inductive load)

Turn-off when switched from $I_T = 10 \text{ A}$ to $V_D = V_{D\max}$: $V_{GR} = 10 \text{ V}$; $L_G \leq 0.5 \mu\text{H}$; $L_S \leq 0.25 \mu\text{H}$; $C_S \geq 20 \text{ nF}$; $T_j = 85^\circ\text{C}$

storage time	t_s	<	0.60	μs
fall time	t_f	<	0.25	μs
peak reverse gate current	I_{GR}	<	10	A

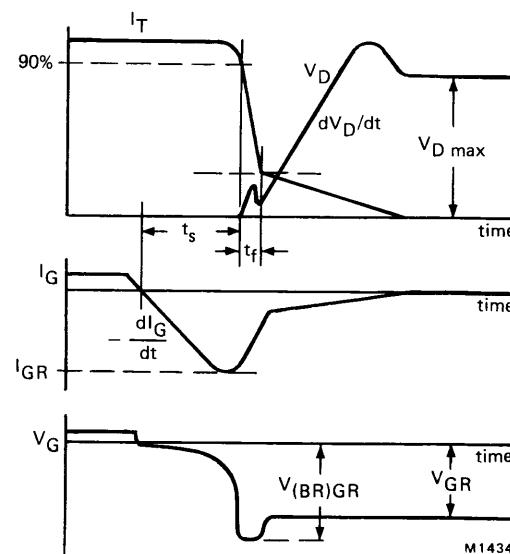


Fig.3 Waveforms.

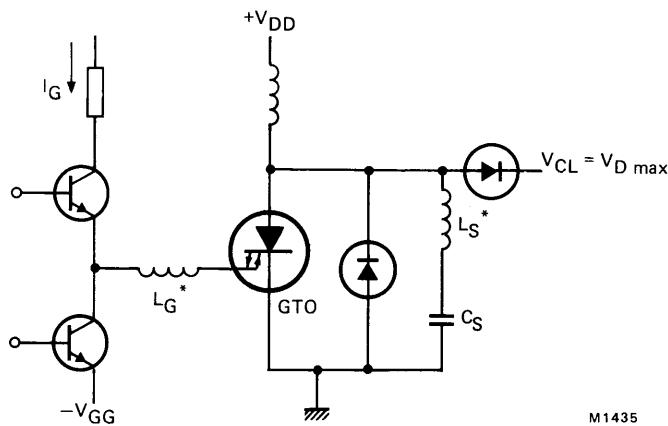


Fig.4 Inductive load test circuit.

*Indicates stray series inductance only.

Switching characteristics (circuit-commutated)*

Turn-off time

$I_T = 50 \text{ A}$; $-dI_T/dt = 10 \text{ A}/\mu\text{s}$; $dV_D/dt = 200 \text{ V}/\mu\text{s}$;
 $V_{GR} = 5 \text{ V}$; $T_j = 120^\circ\text{C}$

$t_q < 1.0 \mu\text{s}$

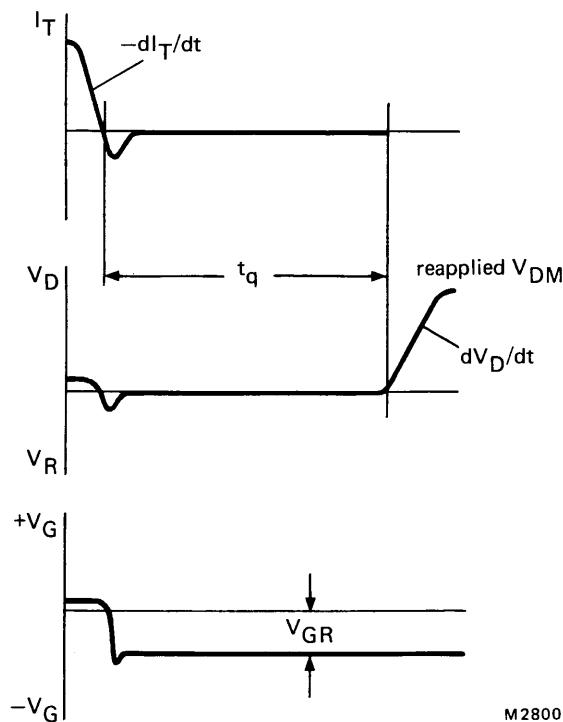


Fig.5 Circuit-commutated turn-off time definition.

*Figs. 7, 11, 12, 13, 15, 16, 17 do not apply to commutated turn-off.

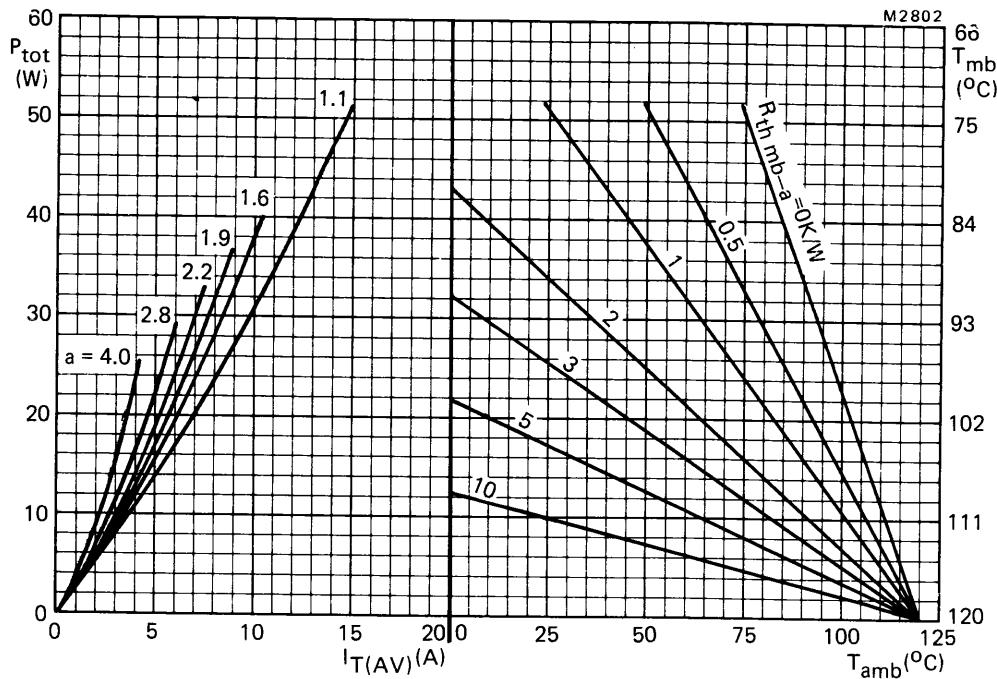


Fig.6 The right hand part shows the interrelationship between the power (derived from the left-hand part) and the maximum permissible temperatures.

$$a = \text{form factor} = \frac{I_T(\text{RMS})}{I_T(\text{AV})}$$

P = power excluding switching losses.

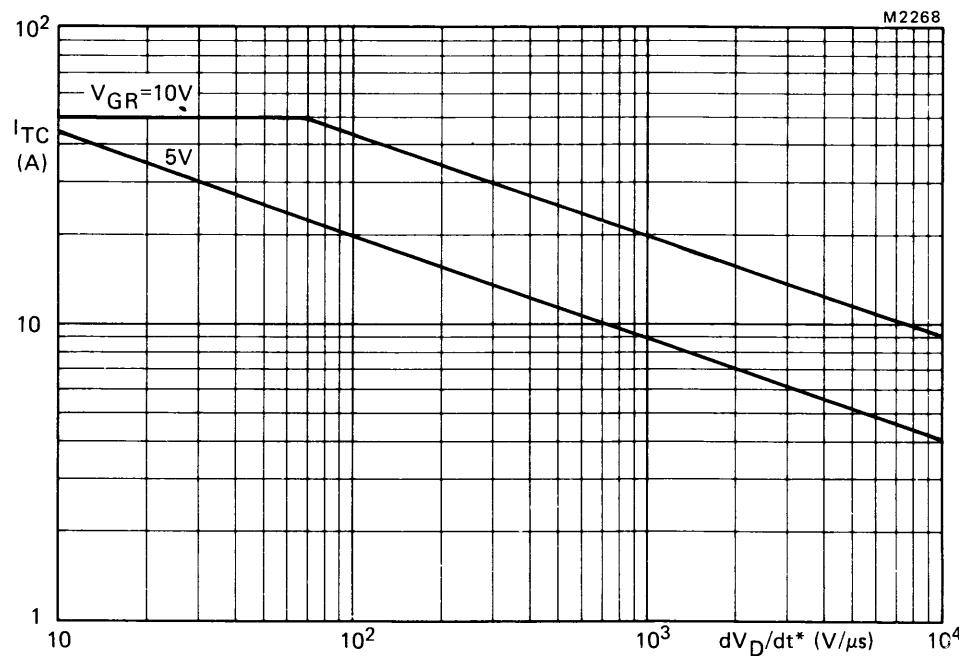


Fig. 7 Anode current which can be turned off versus applied dV_D/dt^* ; inductive load;
 $L_G \leq 0.5 \mu H$; $L_S \leq 0.25 \mu H$; $T_j = 120^\circ C$.

* dV_D/dt is calculated from I_T/C_S .

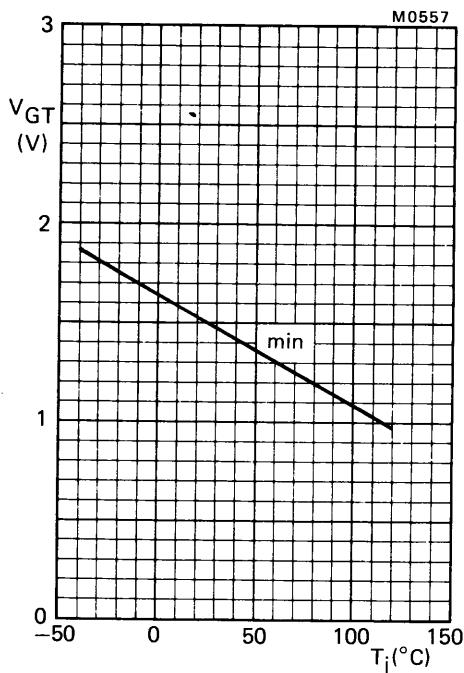


Fig.8 Minimum gate voltage that will trigger all devices as a function of junction temperature; $V_D = 12$ V.

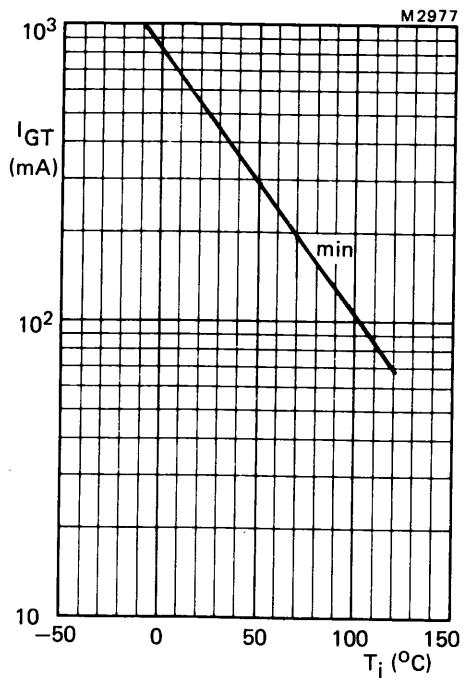


Fig.9 Minimum gate current that will trigger all devices as a function of junction temperature; $V_D = 12$ V.

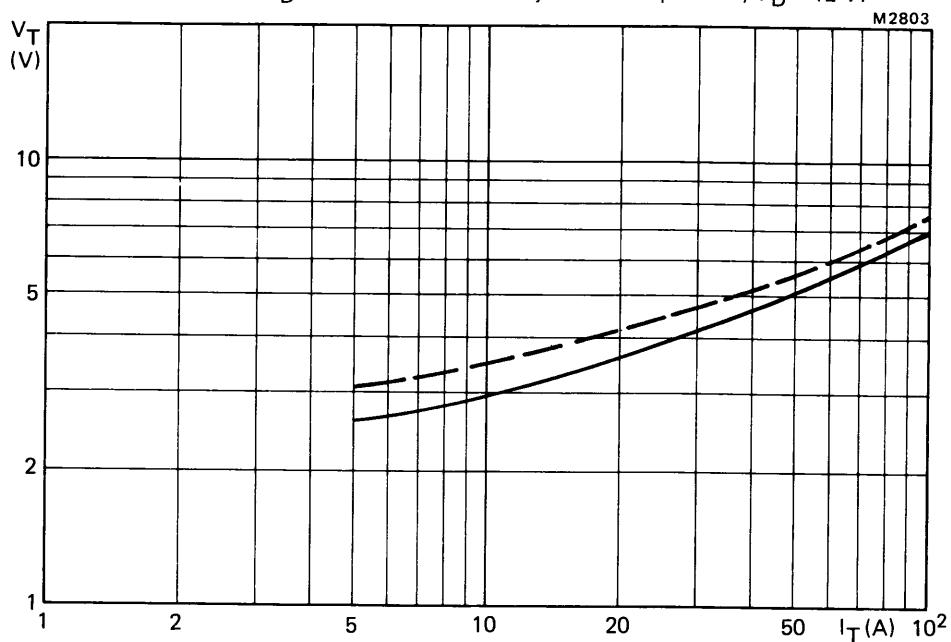


Fig.10 Maximum V_T versus I_T ; --- $T_j = 25$ °C; — $T_j = 120$ °C; $I_G = 0.5$ A.

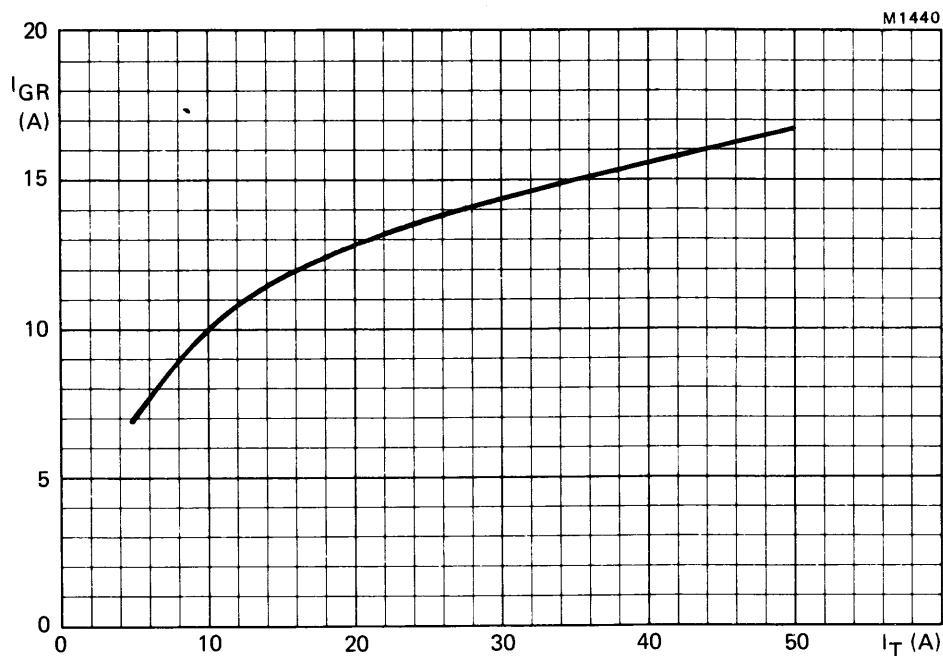


Fig.11 Peak reverse gate current versus anode current at turn-off; inductive load;
 $V_{GR} = 10 \text{ V}$; $I_G = 0.5 \text{ A}$; $L_G = 0.4 \mu\text{H}$; $T_j = 120^\circ\text{C}$; maximum values.



Fig.12 Peak reverse gate current versus applied reverse gate voltage; inductive load;
 $I_T = 10 \text{ A}$; $I_G = 0.5 \text{ A}$; $L_G = 0.4 \mu\text{H}$; $T_j = 120^\circ\text{C}$; maximum values.

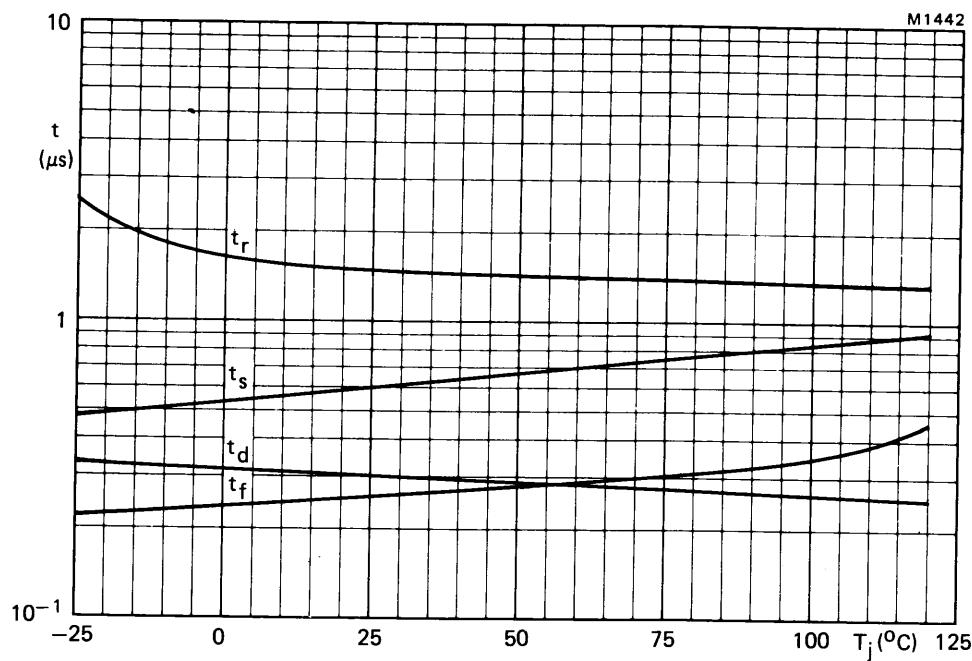


Fig.13 Switching times as a function of junction temperature; $V_D \geq 250 \text{ V}$; $I_T = 10 \text{ A}$; $I_{GF} = 1.0 \text{ A}$; $V_{GR} = 10 \text{ V}$; $I_G = 0.5 \text{ A}$; $L_G = 0.4 \mu\text{H}$; maximum values.

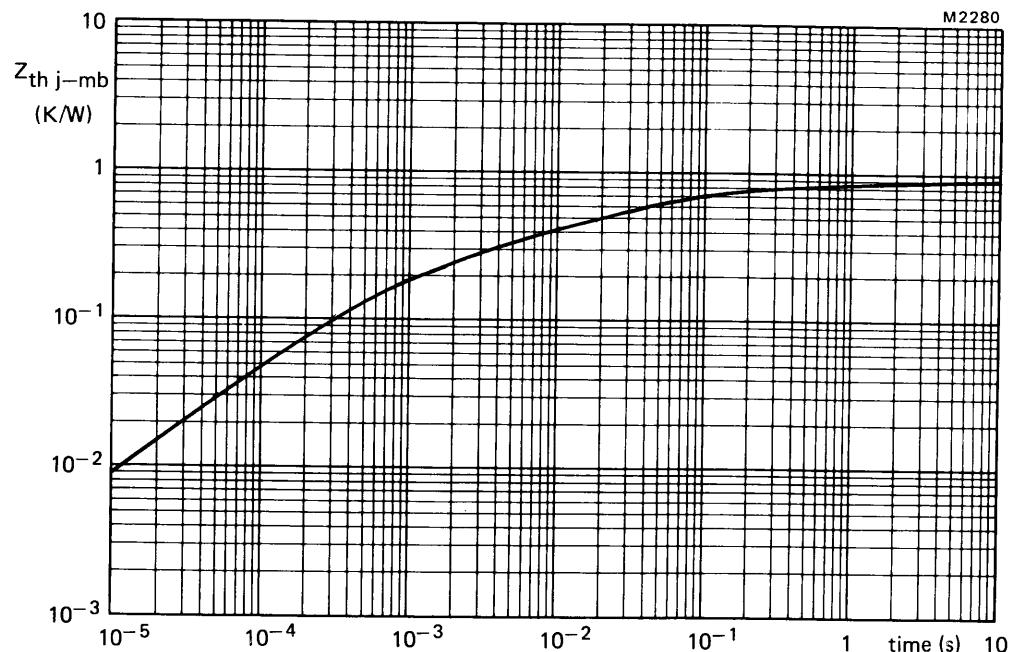


Fig.14 Transient thermal impedance.

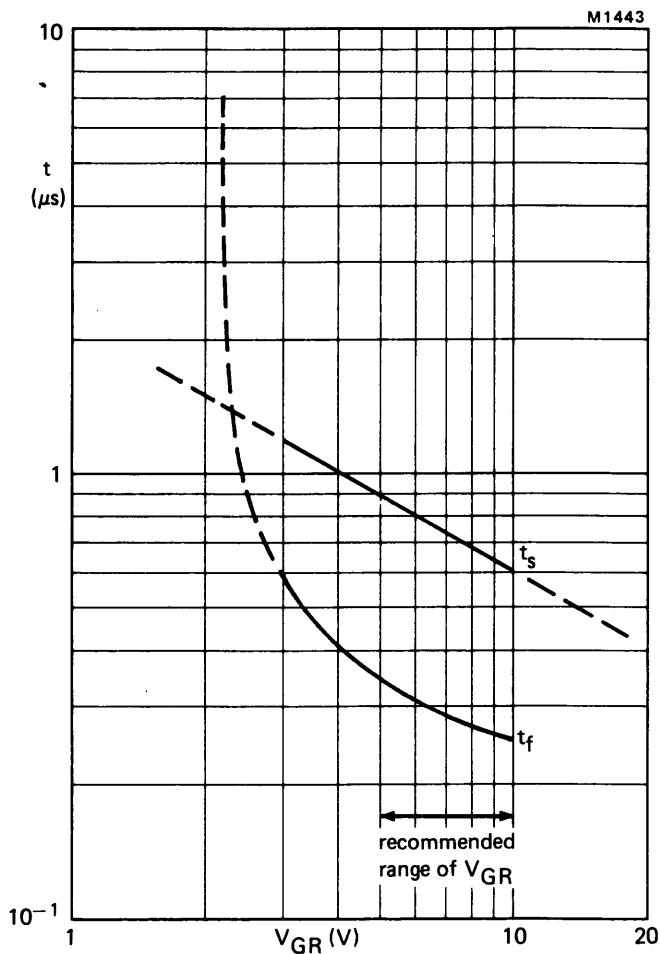


Fig.15 Storage and fall times versus applied reverse gate voltage;
inductive load, $I_T = 10$ A; $I_G = 0.5$ A; $L_G = 0.4 \mu$ H; $T_j = 25$ °C;
maximum values.

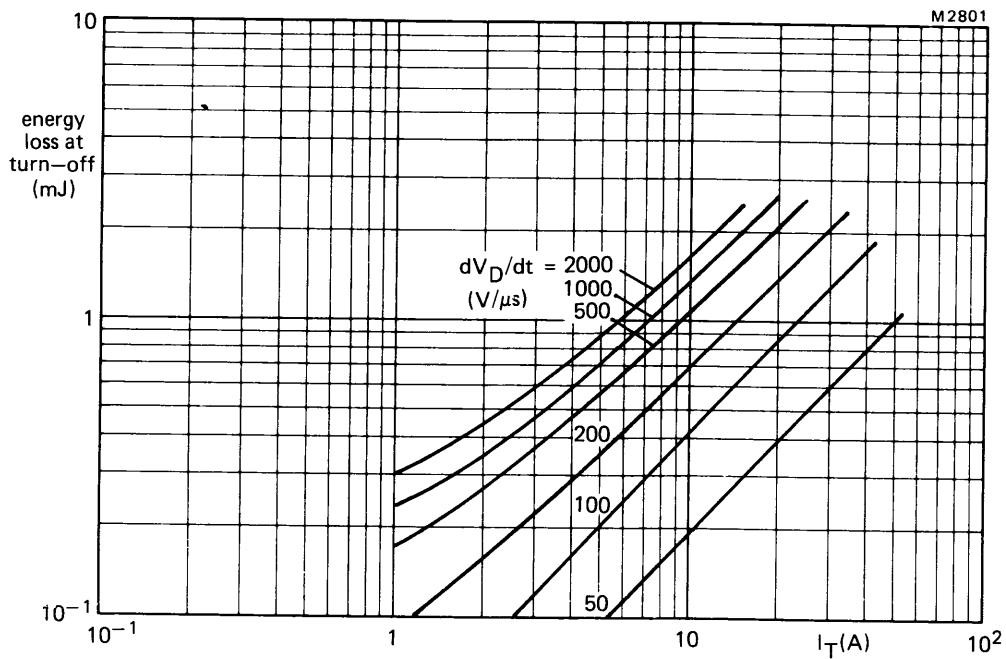


Fig.16 Maximum energy loss at turn-off (per cycle) as a function of anode current and applied dV_D/dt (calculated from I_T/C_S); dV_D/dt linear up to $V_D = V_{DWmax}$; $V_{GR} = 10$ V; $I_G = 0.5$ A; $L_G < 0.5 \mu$ H; $L_S < 0.25 \mu$ H; $T_j = 120$ °C.

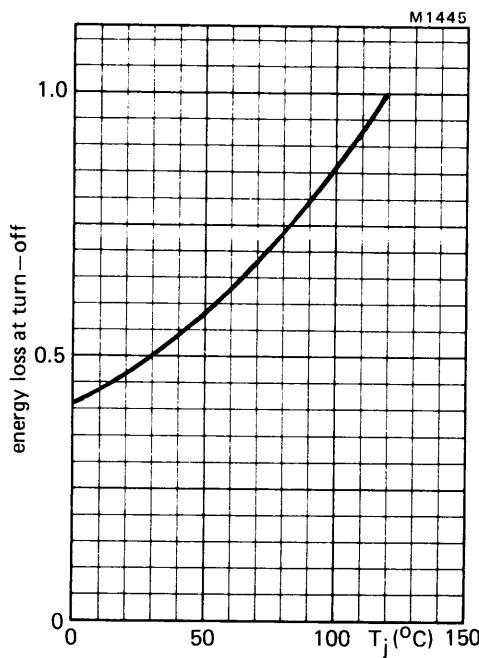


Fig.17 Energy loss at turn-off as a function of junction temperature; $I_G = 0.5$ A; $V_{GR} = 10$ V. Normalised to $T_j = 120$ °C.

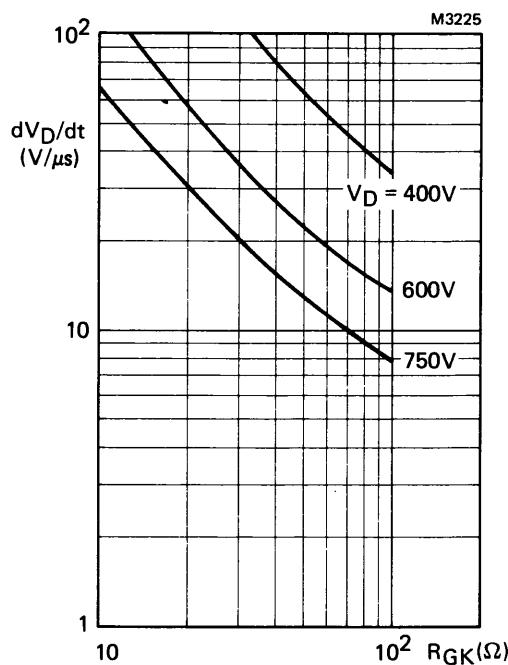


Fig.18 Linear rate of rise of off-state voltage versus gate-cathode resistance; $T_j = 25$ °C; typical values.

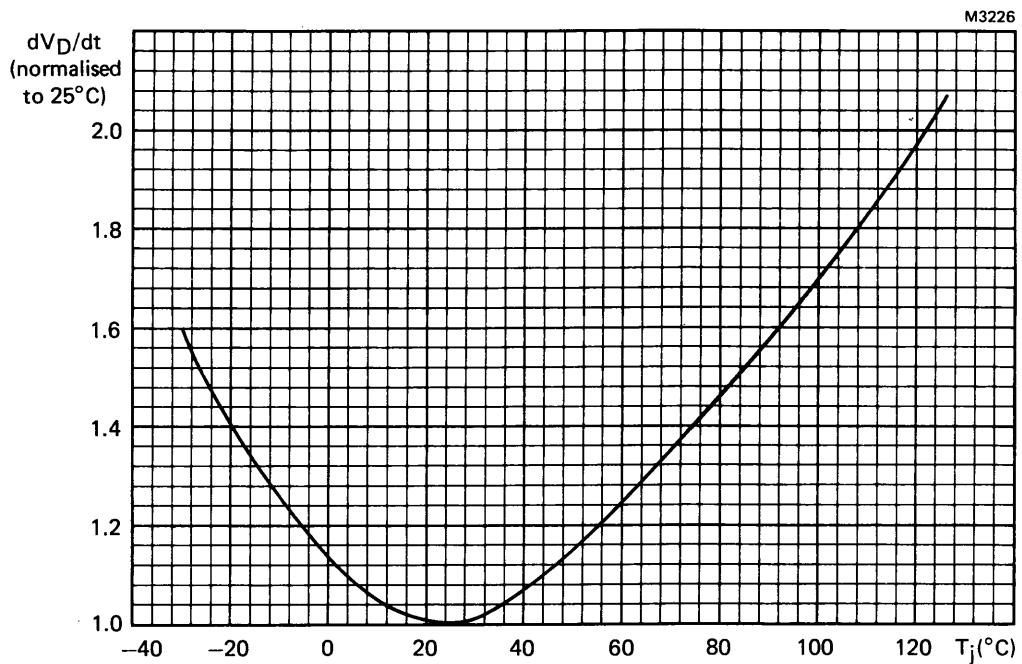


Fig.19 Rate of rise of off-state voltage versus junction temperature, normalised to 25 °C; $V_{Dmax} = 750V$; $R_{GK} = 22 \Omega$; typical values.

FAST GATE TURN-OFF THYRISTORS

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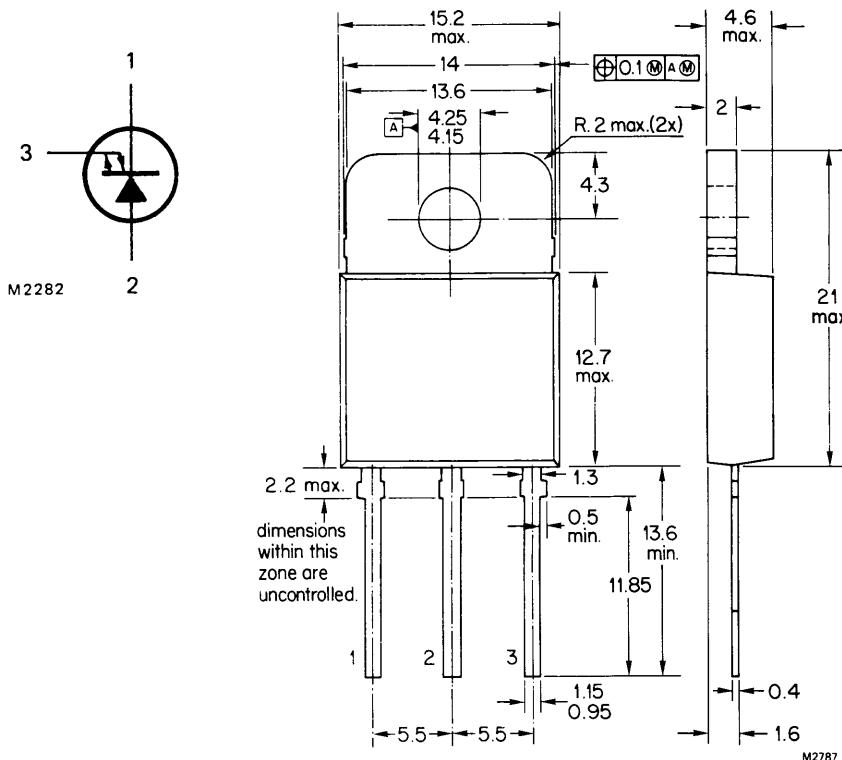
QUICK REFERENCE DATA

		BTS59-850R	1000R	1200R	
Repetitive peak off-state voltage	V _{DRM}	max. 850	1000	1200	V
Non-repetitive peak on-state current	I _{TSM}	max. 100	100	100	A
Controllable anode current	I _{TCRM}	max. 50	50	50	A
Average on-state current	I _{T(AV)}	max. 15	15	15	A
Fall time	t _f	< 250	250	250	ns

MECHANICAL DATA

Dimensions in mm

Fig.1 SOT-93; anode connected to mounting base



Accessories supplied on request: see data sheets Mounting instructions and accessories for SOT-93 envelopes.

RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC134)

Anode to cathode .		BTS59-850R	1000R	1200R	
Transient off-state voltage	V_{DSM}	max. 1000	1100	1300	V^*
Repetitive peak off-state voltage	V_{DRM}	max. 850	1000	1200	V^*
Working off-state voltage	V_{DW}	max. 600	800	1000	V^*
Continuous off-state voltage	V_D	max. 500	650	750	V^*
Average on-state current (averaged over any 20 ms period) up to $T_{mb} = 85^\circ C$	$I_T(AV)$	max.	15		A
Controllable anode current	I_{TCRM}	max.	50		A
Non-repetitive peak on-state current $t = 10$ ms; half-sinewave; $T_j = 120^\circ C$ prior to surge	I_{TSM}	max.	100		A
$I^2 t$ for fusing; $t = 10$ ms	$I^2 t$	max.	50		$A^2 s$
Total power dissipation up to $T_{mb} = 25^\circ C$	P_{tot}	max.	105		W
Gate to cathode					
Repetitive peak current $T_j = 120^\circ C$ prior to surge gate-cathode forward; $t = 10$ ms; half-sinewave	I_{GFM}	max.	25		A
gate-cathode reverse; $t = 20 \mu s$	I_{GRM}	max.	25		A
Average power dissipation (averaged over any 20 ms period)	$P_G(AV)$	max.	5.0		W
Temperatures					
Storage temperature	T_{stg}		-40 to +125		$^\circ C$
Operating junction temperature	T_j	max.	120		$^\circ C$
THERMAL RESISTANCE					
From mounting base to heatsink; with heatsink compound	$R_{th\ mb-h}$	=	0.2		K/W
From junction to mounting base	$R_{th\ j\cdot mb}$	=	0.9		K/W

* Measured with gate-cathode connected together.

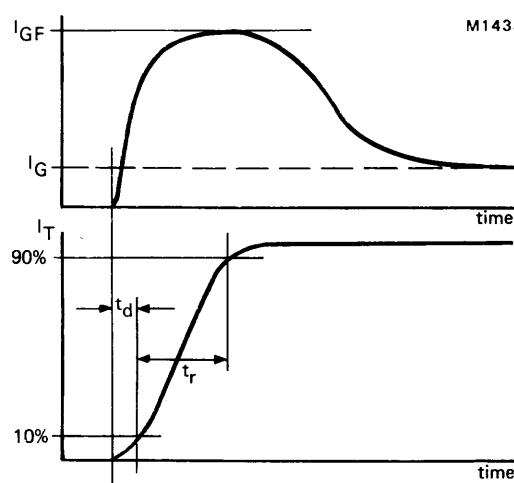
CHARACTERISTICS**Anode to cathode****On-state voltage** $I_T = 10 \text{ A}; I_G = 0.5 \text{ A}; T_j = 120^\circ\text{C}$ $V_T < 2.3 \text{ V}^*$ **Rate of rise of off-state voltage that will not trigger any off-state device; exponential method** $V_D = 2/3 V_{Dmax}; V_{GR} = 5 \text{ V}; T_j = 120^\circ\text{C}$ $dV_D/dt < 10 \text{ kV}/\mu\text{s}$ **Rate of rise of off-state voltage that will not trigger any device following conduction, linear method** $I_T = 20 \text{ A}; V_D = V_{DRMmax}; V_{GR} = 10 \text{ V}; T_j = 120^\circ\text{C}$ $dV_D/dt < 1.0 \text{ kV}/\mu\text{s}$ **Off-state current** $V_D = V_{Dmax}; T_j = 120^\circ\text{C}$ $I_D < 5.0 \text{ mA}$ **Latching current; $T_j = 25^\circ\text{C}$** $I_L \text{ typ. } 1.5 \text{ A}^{**}$ **Gate to cathode****Voltage that will trigger all devices** $V_D = 12 \text{ V}; T_j = 25^\circ\text{C}$ $V_{GT} > 1.5 \text{ V}$ **Current that will trigger all devices** $V_D = 12 \text{ V}, T_j = 25^\circ\text{C}$ $I_{GT} > 300 \text{ mA}$ **Minimum reverse breakdown voltage** $I_{GR} = 1.0 \text{ mA}$ $V_{(BR)GR} > 10 \text{ V}$ **Switching characteristics (resistive load)****Turn-on when switched to $I_T = 10 \text{ A}$ from $V_D = 250 \text{ V}$
with $I_{GF} = 1.5 \text{ A}; T_j = 25^\circ\text{C}$** $t_d < 0.3 \mu\text{s}$
 $t_r < 1.5 \mu\text{s}$ 

Fig.2 Waveforms

* Measured under pulse conditions to avoid excessive dissipation.

** Below latching level the device behaves like a transistor with a gain dependent on current.

Switching characteristics (inductive load)

Turn-off when switched from $I_T = 10 \text{ A}$ to $V_D = V_{D\max}$:

$V_{GR} = 10 \text{ V}$; $L_G \leq 0.5 \mu\text{H}$; $L_S \leq 0.25 \mu\text{H}$; $C_S \geq 20 \text{ nF}$; $T_j = 25^\circ\text{C}$

storage time	t_s	<	0.60	μs
fall time	t_f	<	0.25	μs
peak reverse gate current	I_{GR}	<	10	A

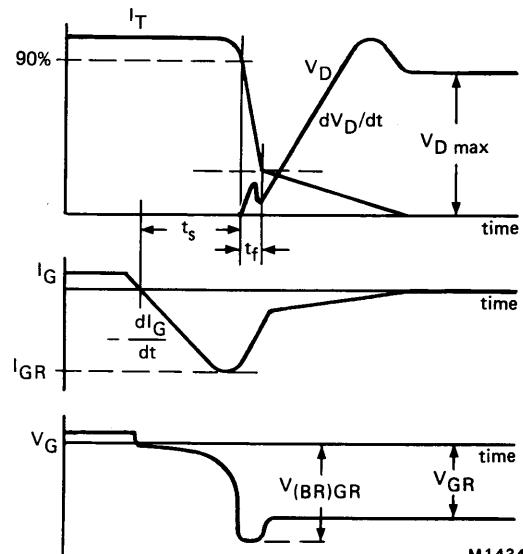


Fig.3 Waveforms.

M1434

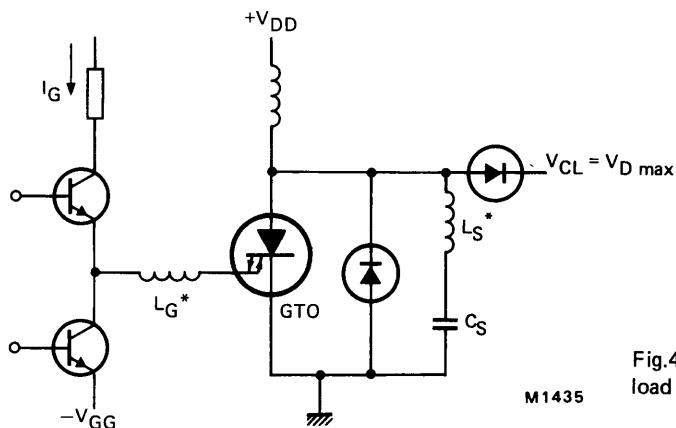


Fig.4 Inductive load test circuit.

M1435

* Indicates stray series inductance only

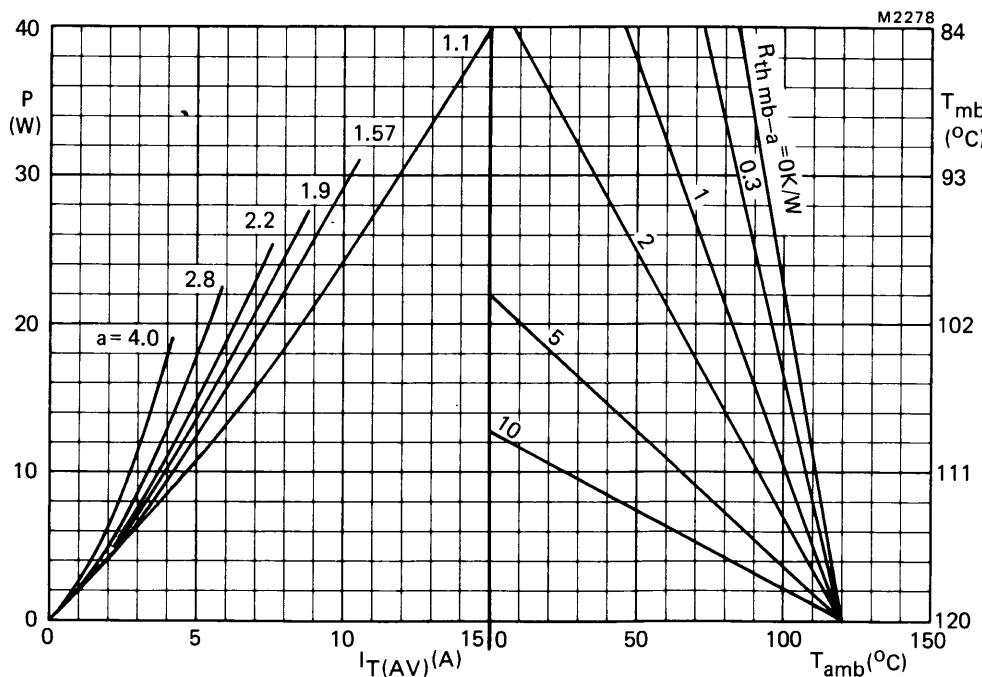


Fig.5 The right hand part shows the interrelationship between the power (derived from the left-hand part) and the maximum permissible temperatures.

$$a = \text{form factor} = \frac{|I_T(\text{RMS})|}{|I_T(\text{AV})|}$$

P = power excluding switching losses.

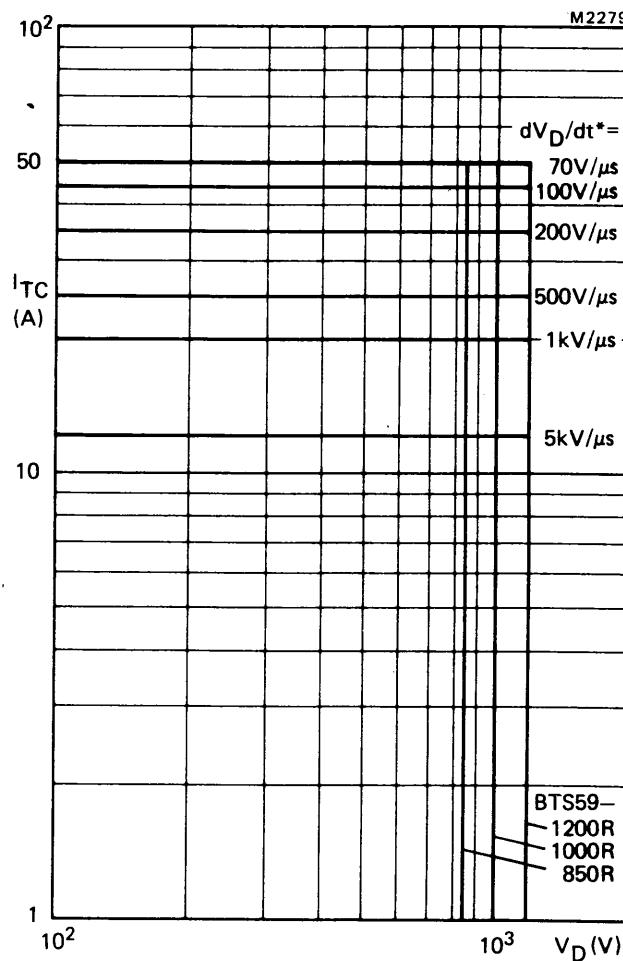


Fig.6 Anode current which can be turned off versus anode voltage; inductive load; $V_{GR} = 10$ V; $L_G \leq 0.5 \mu$ H;
 $L_S \leq 0.25 \mu$ H; $T_j = 120$ °C.

* dV_D/dt is calculated from I_T/C_S .

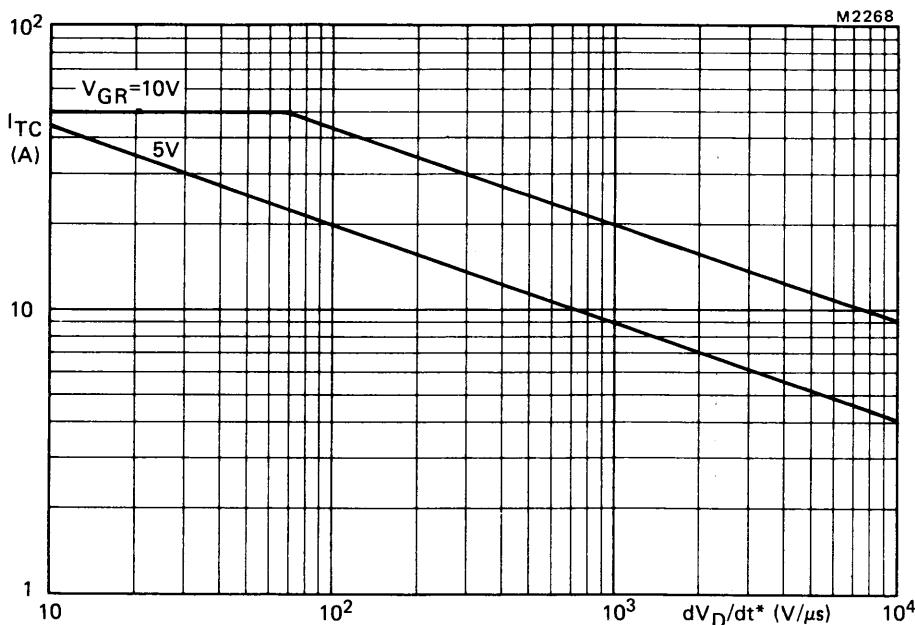


Fig.7 Anode current which can be turned off versus applied dV_D/dt^* ; inductive load;
 $L_G \leq 0.5 \mu H$; $L_S \leq 0.25 \mu H$; $T_j = 120^\circ C$. * dV_D/dt is calculated from I_T/C_S .

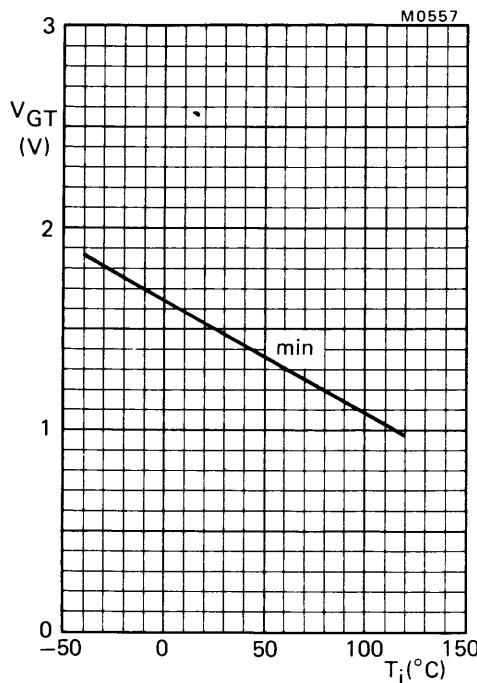


Fig.8 Minimum gate voltage that will trigger all devices as a function of junction temperature; $V_D = 12$ V.

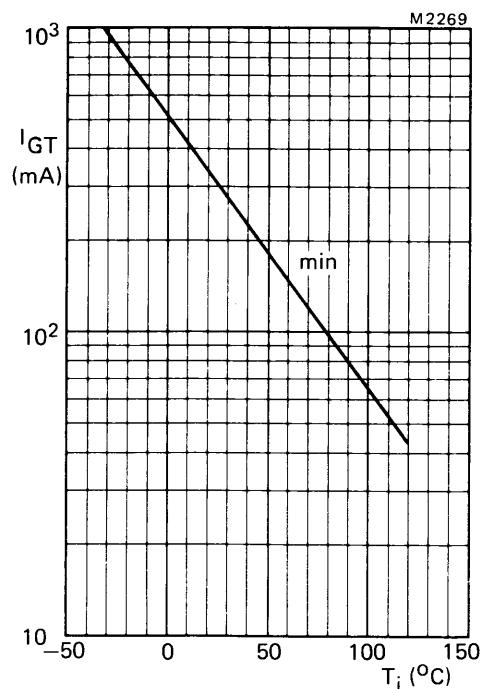


Fig.9 Minimum gate current that will trigger all devices as a function of junction temperature; $V_D = 12$ V.

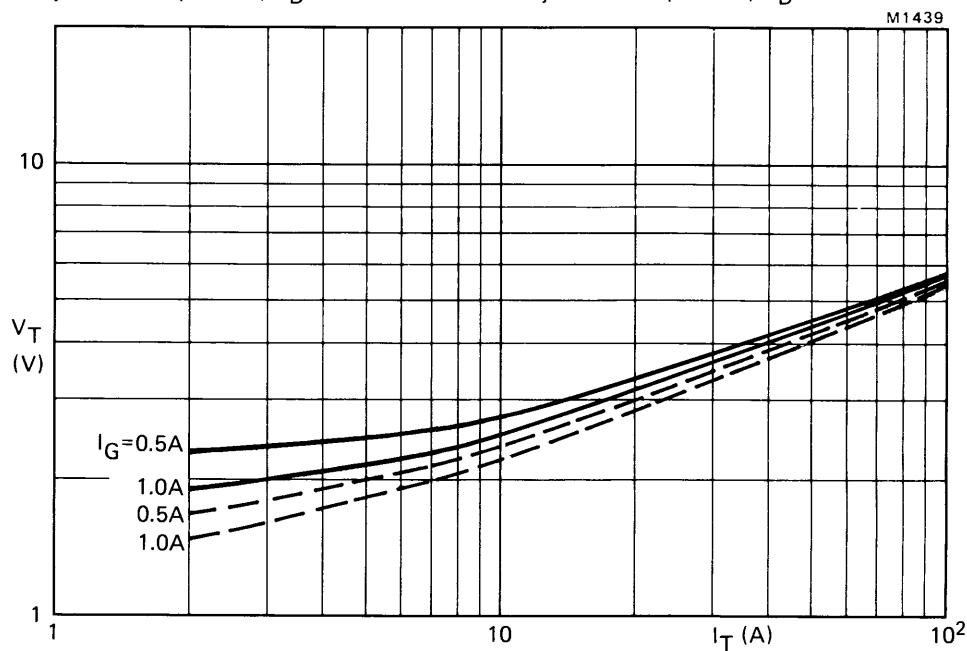


Fig.10 Maximum V_T versus I_T ; —— $T_j = 25$ $^{\circ}$ C; - - - $T_j = 120$ $^{\circ}$ C.

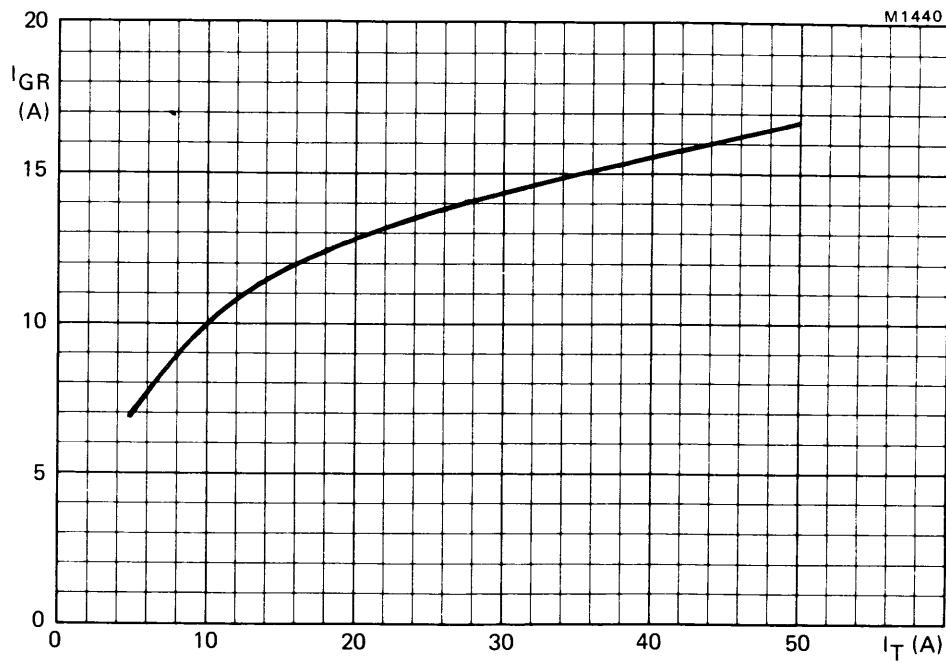


Fig.11 Peak reverse gate current versus anode current at turn-off; inductive load;
 $V_{GR} = 10$ V; $I_G = 0.5$ A; $L_G = 0.4 \mu\text{H}$; $T_j = 120$ °C; maximum values.

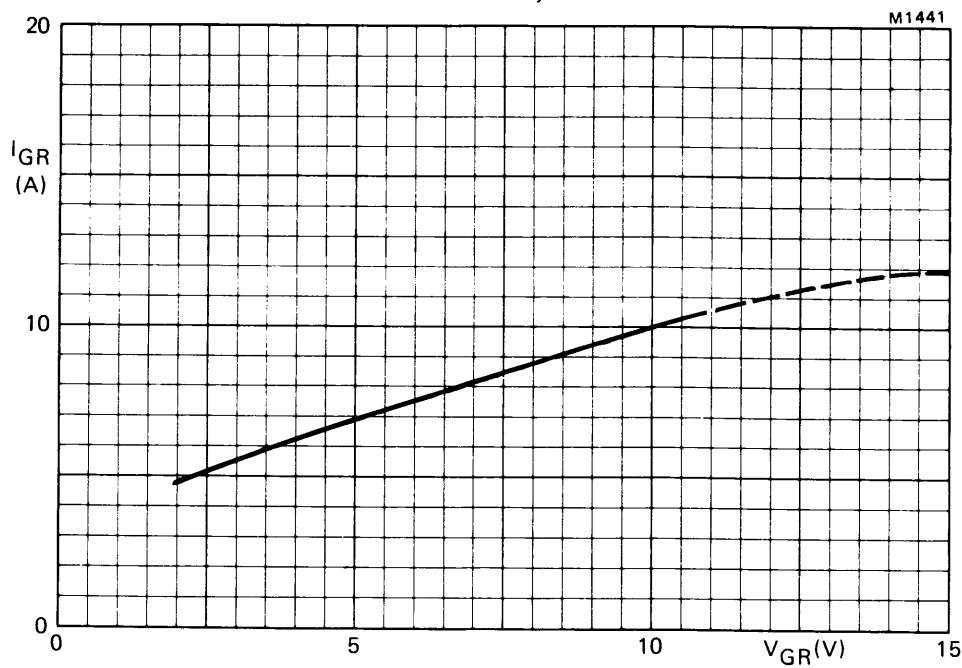


Fig.12 Peak reverse gate current versus applied reverse gate voltage; inductive load;
 $I_T = 10$ A; $I_G = 0.5$ A, $L_G = 0.4 \mu\text{H}$; $T_j = 120$ °C; maximum values.

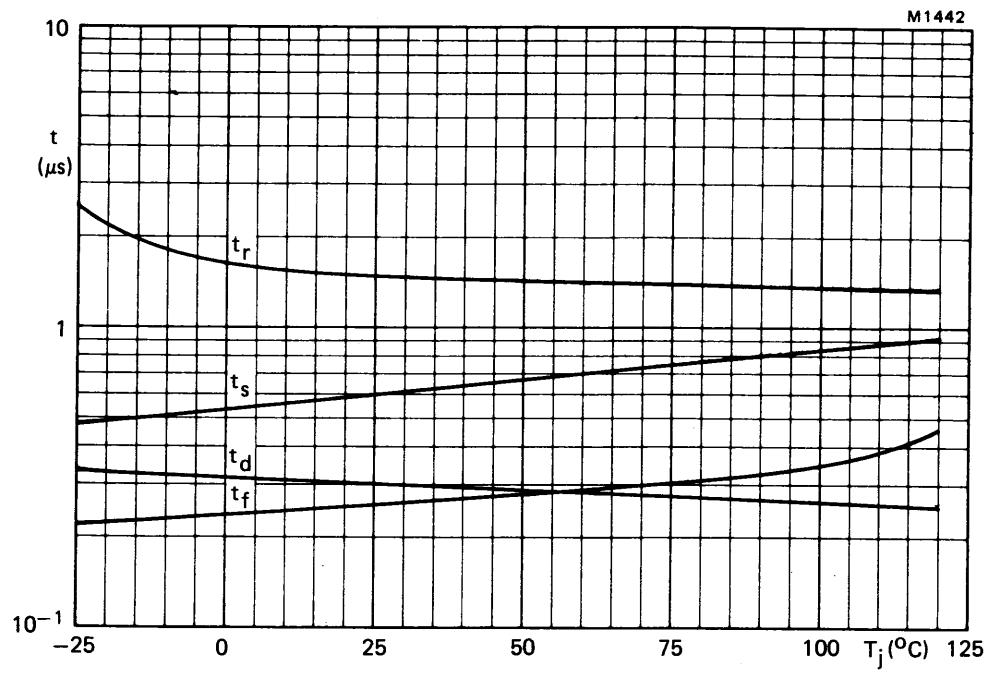


Fig.13 Switching times as a function of junction temperature; $V_D \geq 250$ V; $I_T = 10$ A;
 $I_{GF} = 1.0$ A; $V_{GR} = 10$ V; $I_G = 0.5$ A; $L_G = 0.4$ μ H; maximum values.

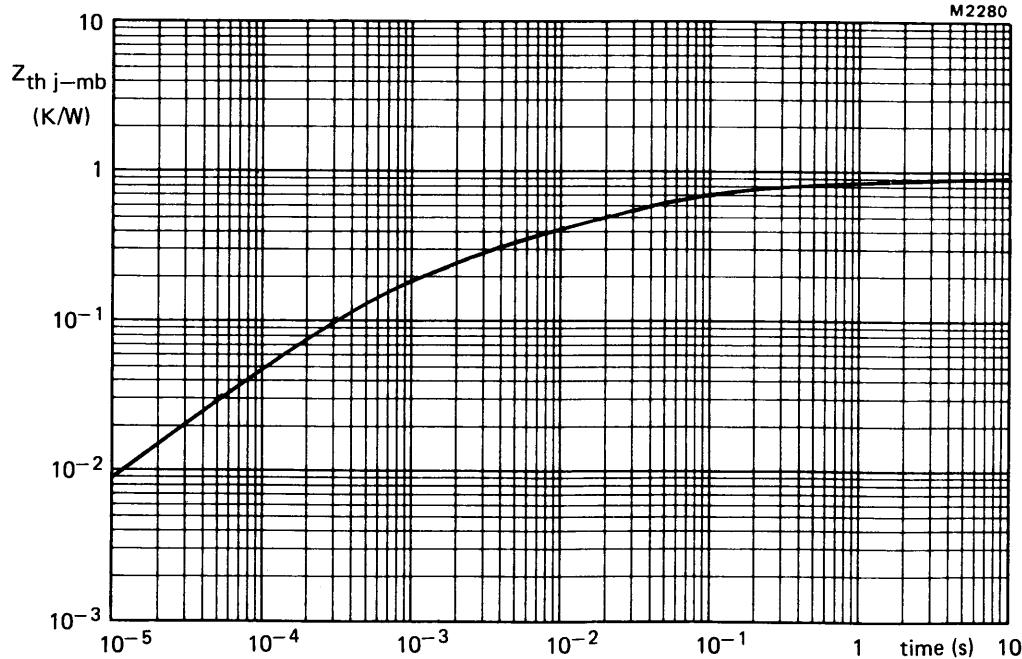


Fig.14 Transient thermal impedance.

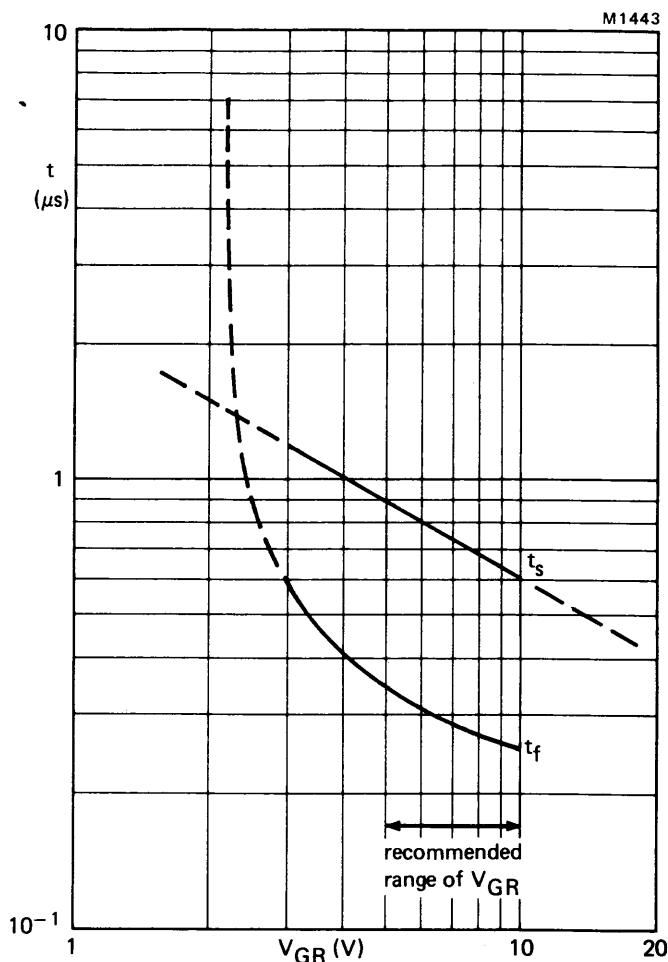


Fig.15 Storage and fall times versus applied reverse gate voltage;
inductive load; $I_T = 10$ A; $I_G = 0.5$ A; $L_G = 0.4 \mu$ H; $T_j = 25$ °C;
maximum values.

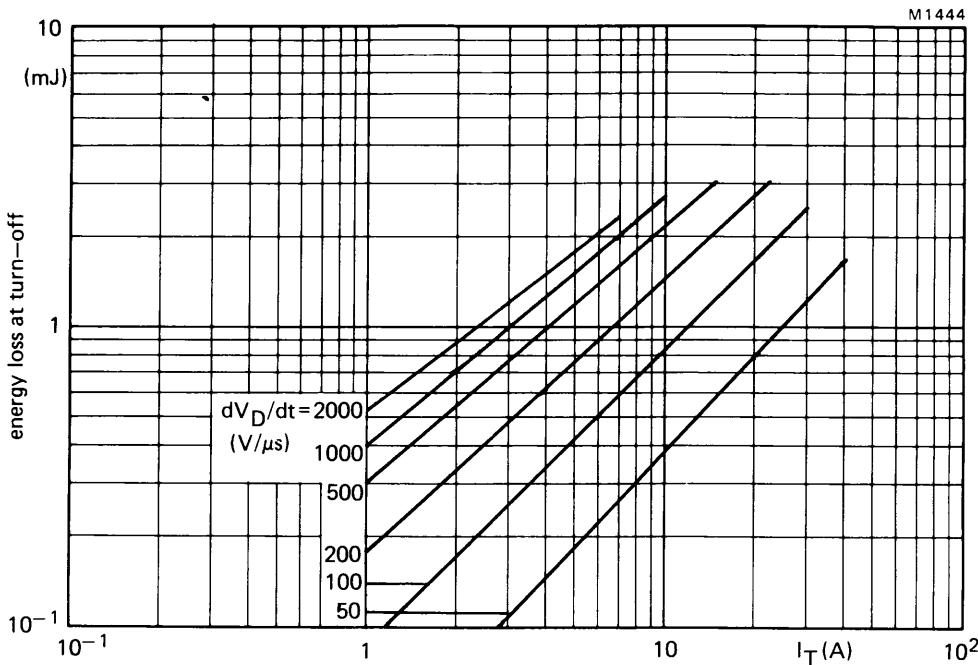


Fig.16 Maximum energy loss at turn-off (per cycle) as a function of anode current and applied dV_D/dt (calculated from I_T/C_S); dV_D/dt linear up to $V_{D\max} = 600$ V; $V_{GR} = 10$ V; $I_G = 0.5$ A; $L_G \leqslant 0.5 \mu\text{H}$; $L_S \leqslant 0.25 \mu\text{H}$; $T_j = 120^\circ\text{C}$.

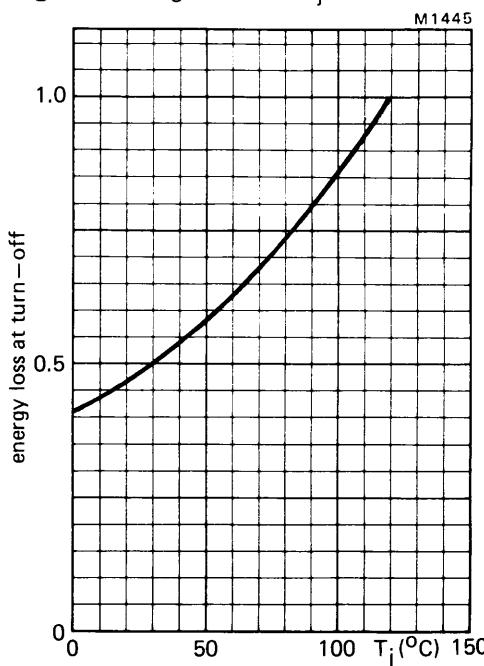


Fig.17 Energy loss at turn off as a function of junction temperature; $I_G = 0.5$ A; $V_{GR} = 10$ V. Normalised to $T_j = 120^\circ\text{C}$.

Silicon diffused power transistors**BUT18F; BUT18AF****DESCRIPTION**

High-voltage, high-speed, glass-passivated NPN power transistor in a SOT186 package with electrically isolated mounting base.

APPLICATIONS

- Converters
- Inverters
- Switching regulators
- Motor control systems.

PINNING

PIN	DESCRIPTION
1	base
2	collector
3	emitter
mb	mounting base; electrically isolated from all pins

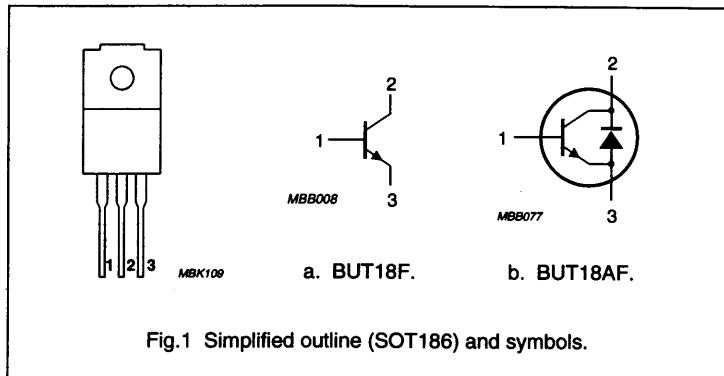


Fig.1 Simplified outline (SOT186) and symbols.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MAX.	UNIT
V_{CESM}	collector-emitter peak voltage BUT18F BUT18AF	$V_{BE} = 0$	850 1000	V
V_{CEO}	collector-emitter voltage BUT18F BUT18AF	open base	400 450	V
V_{CEsat}	collector-emitter saturation voltage	see Fig.7	1.5	V
I_{Csat}	collector saturation current		4	A
I_C	collector current (DC)	see Fig.4	6	A
I_{CM}	collector current (peak value)	see Fig.4	12	A
P_{tot}	total power dissipation	$T_h \leq 25^\circ\text{C}$; see Fig.2	33	W
t_f	fall time	resistive load; see Figs 10 and 11	0.8	μs

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
$R_{th j-h}$	thermal resistance from junction to external heatsink	note 1	6.15	K/W
		note 2	3.65	K/W

Notes

1. Mounted **without** heatsink compound and 30 ± 5 N force on centre of package.
2. Mounted **with** heatsink compound and 30 ± 5 N force on centre of package.

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LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{CESM}	collector-emitter peak voltage BUT18F	V _{BE} = 0	-	850	V
	BUT18AF			1000	V
V _{CEO}	collector-emitter voltage BUT18F	open base	-	400	V
	BUT18AF			450	V
I _{Csat}	collector saturation current		-	4	A
I _C	collector current (DC)	see Fig.4	-	6	A
I _{CM}	collector current (peak value)	see Fig.4	-	12	A
I _B	base current (DC)		-	3	A
I _{BM}	base current (peak value)		-	6	A
P _{tot}	total power dissipation	T _h ≤ 25 °C; see Fig.2; note 1	-	20	W
		T _h ≤ 25 °C; see Fig.2; note 2	-	33	W
T _{stg}	storage temperature		-65	+150	°C
T _j	junction temperature		-	150	°C

Notes

1. Without heatsink compound.
2. With heatsink compound.

ISOLATION CHARACTERISTICS

SYMBOL	PARAMETER	TYP.	MAX.	UNIT
V _{IsolM}	isolation voltage from all terminals to external heatsink (peak value)	-	1500	V
C _{isol}	isolation capacitance from collector to external heatsink	12	-	pF

CHARACTERISTICST_j = 25 °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{CEO} sust	collector-emitter sustaining voltage BUT18F	I _C = 100 mA; I _{Boff} = 0; L = 25 mH; see Figs 3 and 6	400	-	-	V
			450	-	-	V
V _{CESat}	collector-emitter saturation voltage	I _C = 4 A; I _B = 800 mA; see Fig.7	-	-	1.5	V
V _{BEsat}	base-emitter saturation voltage	I _C = 4 A; I _B = 800 mA; see Fig.8	-	-	1.3	V
I _{CES}	collector-emitter cut-off current	V _{CE} = V _{CESMmax} ; V _{BE} = 0; note 1	-	-	1	mA
		V _{CE} = V _{CESMmax} ; V _{BE} = 0; T _j = 125 °C; note 1	-	-	2	mA
I _{EBO}	emitter-base cut-off current	V _{EB} = 9 V; I _C = 0	-	-	10	mA

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SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
h_{FE}	DC current gain	$V_{CE} = 5 \text{ V}; I_C = 10 \text{ mA};$ see Fig.9	10	18	35	
		$V_{CE} = 5 \text{ V}; I_C = 1 \text{ A};$ see Fig.9	10	20	35	
Switching times resistive load (see Figs 10 and 11)						
t_{on}	turn-on time	$I_{Con} = 4 \text{ A};$ $I_{Bon} = -I_{Boff} = 800 \text{ mA}$	-	-	1	μs
t_s	storage time	$I_{Con} = 4 \text{ A};$ $I_{Bon} = -I_{Boff} = 800 \text{ mA}$	-	-	4	μs
t_f	fall time	$I_{Con} = 4 \text{ A};$ $I_{Bon} = -I_{Boff} = 800 \text{ mA}$	-	-	0.8	μs
Switching times inductive load (see Figs 10 and 13)						
t_s	storage time	$I_{Con} = 4 \text{ A}; I_{Bon} = 800 \text{ mA}$	-	1.6	2.5	μs
t_f	fall time	$I_{Con} = 4 \text{ A}; I_{Bon} = 800 \text{ mA}$	-	150	400	ns

Note

1. Measured with a half-sinewave voltage (curve tracer).

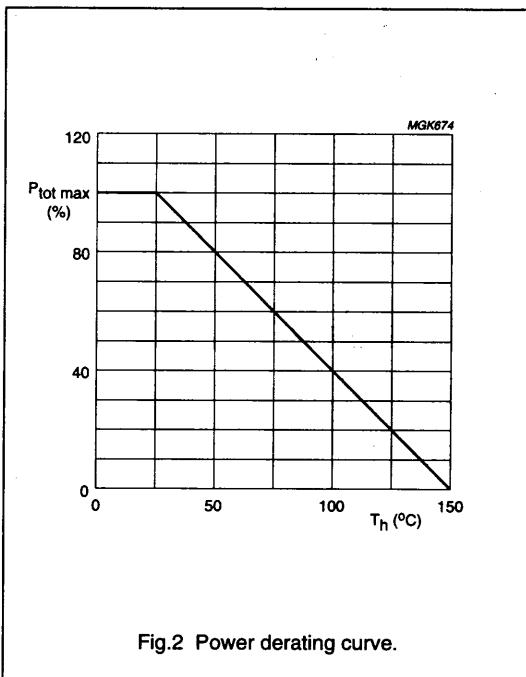


Fig.2 Power derating curve.

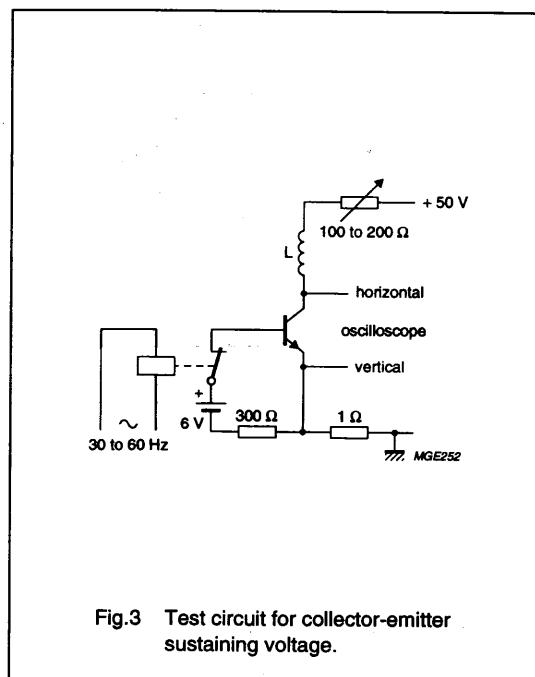
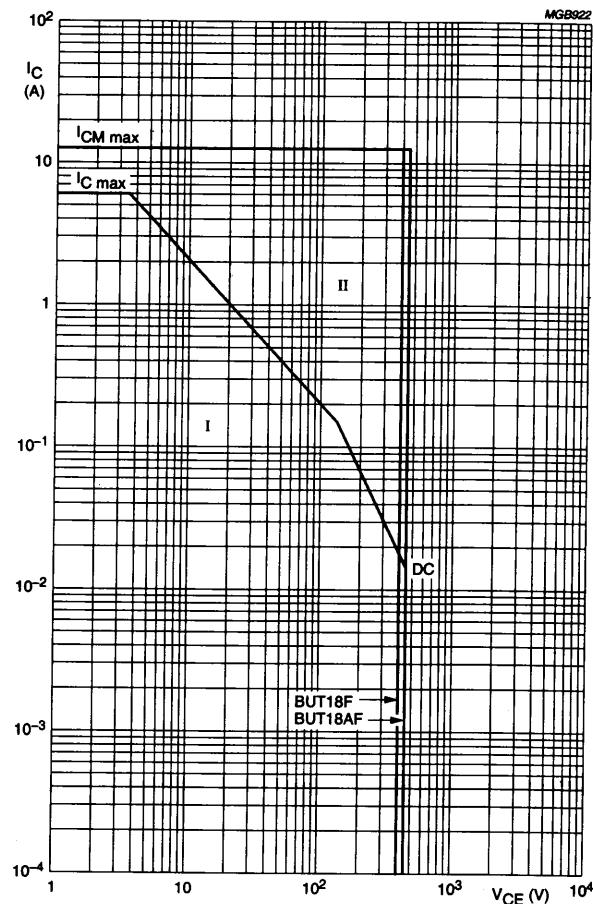


Fig.3 Test circuit for collector-emitter sustaining voltage.

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Mounted without heatsink compound and 30 ± 5 N force on centre of package.

$T_{mb} < 25^\circ C$

I - Region of permissible DC operation.

II - Permissible extension for repetitive pulse operation.

Fig.4 Forward bias SOAR.

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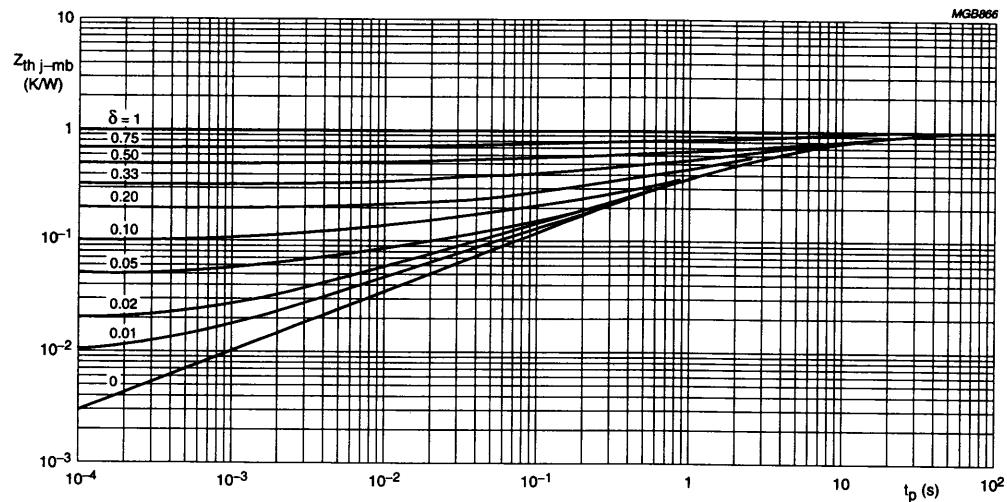


Fig.5 Transient thermal impedance.

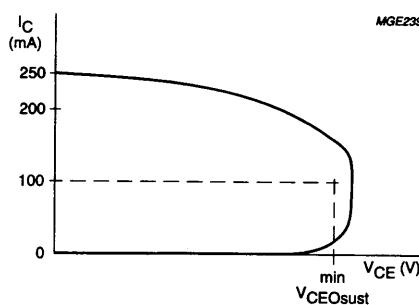


Fig.6 Oscilloscope display for collector-emitter sustaining voltage.

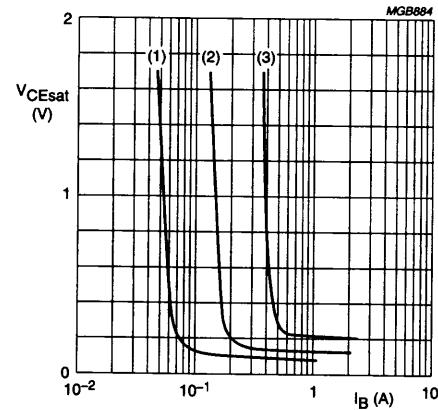


Fig.7 Collector-emitter saturation voltage as a function of base current.

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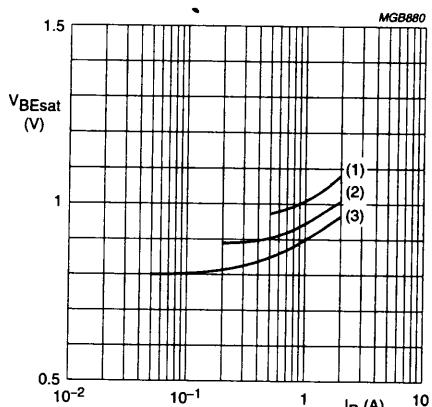
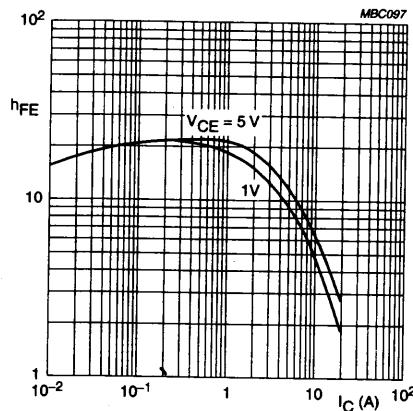
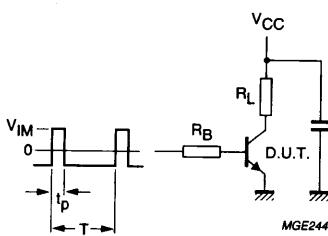


Fig.8 Base-emitter saturation voltage as a function of base current.



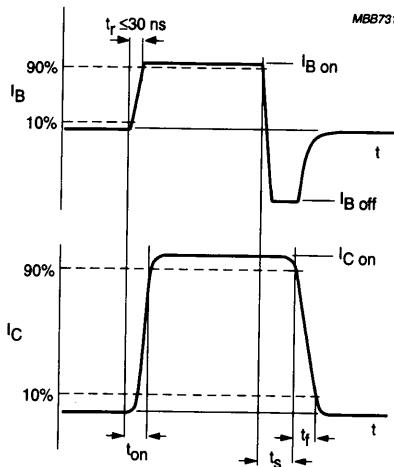
$V_{CE} = 5$ V; $T_j = 25$ °C.

Fig.9 DC current gain; typical values.



$V_{CC} = 250$ V; $t_p = 20$ µs; $V_{IM} = -6$ to +8 V; $t_p/T = 0.01$.
The values of R_B and R_L are selected in accordance with I_{Con} and I_{Bon} requirements.

Fig.10 Test circuit resistive load.



$t_r \leq 20$ ns.

Fig.11 Switching times waveforms with resistive load.